Please note that Cypress is an Infineon Technologies Company.
The document following this cover page is marked as “Cypress” document as this is the company that originally developed the product. Please note that Infineon will continue to offer the product to new and existing customers as part of the Infineon product portfolio.

Continuity of document content
The fact that Infineon offers the following product as part of the Infineon product portfolio does not lead to any changes to this document. Future revisions will occur when appropriate, and any changes will be set out on the document history page.

Continuity of ordering part numbers
Infineon continues to support existing part numbers. Please continue to use the ordering part numbers listed in the datasheet for ordering.

Cypress Semiconductor
Product Qualification Report

QTP#162806 VERSION*A
August 2022

PSoC5 LP Device Family S8PM-10P Technology, Fab25	
CY8C5265 /CY8C5266 CY8C5267 / CY8C5268 CY8C5288/7	PsoC® 5LP CY8C52LP Family Programmable System-on-Chip (PsoC®)
CY8C5465 / CY8C5466 CY8C5467 / CY8C5468 CY8C5488	PsoC® 5LP CY8C54LP Family Programmable System-on-Chip (PsoC®)
CY8C5666 / CY8C5667 CY8C5668 / CY8C5688 CY8C5686 / CY8C5687	PsoC® 5LP CY8C56LP Family Programmable System-on-Chip (PsoC®)
CY8C5866 / CY8C5867 CY8C5868	PsoC® 5LP CY8C58LP Family Programmable System-on-Chip (PsoC®)
CY8C5886 / CY8C5887 CY8C5888	PsoC® 5LP CY8C58LP Family Programmable System-on-Chip (PsoC®)

FOR ANY QUESTIONS ON THIS REPORT, PLEASE CONTACT
reliability@cypress.com or via a CYLINK CRM CASE

Prepared By:
Honesto Sintos
Reliability Engineer

Reviewed By:
Sandhya Chandrashekhar
Reliability Principal Engineer

Approved By:
David Hoffman
Reliability Director

PACKAGE/PRODUCT QUALIFICATION HISTORY

QTP Number	Description of Qualification Purpose	Date
151008	Qualification of S8* Technology in Fab25 Using TSG6M Device	Dec 2015
151403	Qualification of PSoC® 4100 and PSoC® 4200 Device, S8PF-10R Technology in Fab25	Dec 2015
151303	Qualification of CapSense® MBR3 Device, S8PF-10R Technology in Fab25	Dec 2015
160401	Qualification of PSoC™ Multitouch Fingerprint Device, S8PFHD-10R Technology in Fab25	May 2016
160301	Qualification of PSoC™ Multitouch Gen6XL Touchscreen Controller Device, S8SPF-10P Technology in Fab25	Jun 2016
160803	Qualification of PSoC® 4000S Device, S8PFHD-10R Technology in Fab25	Jun 2016
160207	Qualification of PSoC3 Leopard T06, S8P12-10P Technology in Fab25	Jul 2016
160702	Qualification of PSoC® 4200L, S8SPF-10P Technology in Fab25 (AL BEOL Interconnect)	Sep 2016
160701	Qualification of PSoC® 4200L, S8SPF-10P Technology in Fab25 (Cu BEOL Interconnect)	Apr 2017
172307	Qualification of PSoC® 4200L Fix TO Metal Mask Non-Minor Add-On, S8SPF-10P Technology in Fab25. (Cu BEOL Interconnect)	Nov 2017
173204	Qualification of PSoC® 4100S Plus Device, S8SPFHD-10 in Fab25 (Cu BEOL Interconnect)	Dec 2017
162806	Qualification of PSoC5 LP Device Family, S8PM-10P Technology in Fab25	Jun 2018

PRODUCT DESCRIPTION (for qualification)	
Qualification Purpose: Qualification of PSoC5 LP Device Family, S8PM-10P Technology in Fab25	
Marketing Part #:	CY8C526x, CY8C546x, CY8C566x, CY8C586x, CY8C5488, CY8C5288/7
Device Description:	1.71V to 5.5V, Industrial Programmable System on a Chip
Cypress Division:	Cypress Semiconductor Corporation – MCU and Connectivity Division (MCD)

TECHNOLOGY/FAB PROCESS DESCRIPTION			
Number of Metal Layers:	Proprietary	Metal Composition:	Proprietary
Passivation Type and Thickness:			Proprietary
Generic Process Technology/Design Rule (μ-drawn):			Proprietary
Gate Oxide Material/Thickness (MOS):			Proprietary
Name/Location of Die Fab (prime) Facility:			Cypress, Fab 25
Die Fab Line ID/Wafer Process ID:			Fab25 / S8PM-10P

PACKAGE AVAILABILITY

PACKAGE	ASSEMBLY SITE	QTP NUMBER
100-Lead TQFP (14x14x1.4mm)	**CML-Philippines (R)**	**112302**
100-Lead TQFP (14x14x1.4mm)	**JCET-China (JT)**	**111817**

MAJOR PACKAGE INFORMATION USED IN THIS QUALIFICATION	
Package Designation:	AZ100
Package Outline, Type, or Name:	100L TQFP 14x14mm / Thin Quad Flatpack package
Mold Compound Name/Manufacturer:	KE-G6000 / Kyocera
Mold Compound Flammability Rating:	V-O per UL94
Oxygen Rating Index:	None
Lead Frame Material:	Copper
Lead Finish, Composition	NiPdAu
Die Backside Preparation Method/Metallization:	Backgrind
Die Separation Method:	Sawing
Die Attach Supplier:	Dexter
Die Attach Material:	QMI509
Die Attach Method:	Die Attach Epoxy
Bond Diagram Designation:	001-75839, 001-75838
Wire Bond Method:	Thermosonic
Wire Material/Size:	Au. 0.8 mil
Thermal Resistance Theta JA °C/W:	44.66°C/W
Package Cross Section Yes/No:	N/A
Assembly Process Flow:	001-73775
Name/Location of Assembly (prime) facility:	CML-RA
MSL Level	3
Reflow Profile	260C

ELECTRICAL TEST / FINISH DESCRIPTION	
Test Location:	ASEK-Taiwan (G), CML-Philippines (RA)

RELIABILITY TESTS PERFORMED PER SPECIFICATION REQUIREMENTS

Stress/Test	Test Condition (Temp/Bias)	Result P/F
High Temperature Operating Life Early Failure Rate (EFR)	Dynamic Operating Condition, 150°C, 2.07V, 48 Hours JESD22-A-108-B	P
High Temperature Operating Life Latent Failure Rate (LFR)	Dynamic Operating Condition, 150°C, 2.07V, 500 Hours JESD22-A-108-B	P
Low Temperature Operating Life	-40°C	P
Endurance	Per datasheet, JESD22-A117	P
Data Retention	JESD22-A117 and JESD22-A103, 150C, 1000 Hours	P
Temperature Cycle	-65^{0}C to 150^{0}C, JESD22-A-104, 500 Cycles / 1000Cycles Precondition: JESD22 Moisture Sensitivity Level 3 192 Hrs, 30C/60%RH+3IR-Reflow, 260°C+0, -5°C	P
High Accelerated Saturation Test (HAST)	130C, 5.5V, 85%RH, JESD22-A-110-B, 96 Hours Precondition: JESD22 Moisture Sensitivity Level 3 192 Hrs, 30C/60%RH+3IR-Reflow, 260°C+0, -5°C	P
Pressure Cooker	121C/100%RH, JESD22-A102-C, 168 Hours Precondition: JESD22 Moisture Sensitivity Level 3 192 Hrs, 30C/60%RH+3IR-Reflow, 260°C+0, -5°C	P
Electrostatic Discharge Human Body Model (ESD-HBM)	2200V, 3300V, JESD22-A114E	P
Electrostatic Discharge Charge Device Model (ESD-CDM)	500V JESD22-C101C	P
Static Latch-up	± 140mA, 125C/85°C, JESD78	P
Acoustic (M3)	J-STD-020	P

RELIABILITY FAILURE RATE SUMMARY

Stress/Test	Device Tested/ Device Hours	# Fails	Activation Energy	Thermal AF[3]	Failure Rate
High Temperature Operating Life Early Failure Rate	1,545 Devices	0	N/A	N/A	0 PPM 1
High Temperature Operating Life Long Term Failure Rate	570,000	0	0.7	170	9 FIT 2

1. EFR devices number is based on QTP#162806 EFR data.
2. LFR device hours are based on QTP#151008, QTP#151403, QTP#151303, QTP#160301, QTP#160207, QTP#160702, QTP#160701, QTP#172307 and QTP#162806 LFR data.

[1] Assuming an ambient temperature of 55°C and a junction temperature rise of 15°C.
[2] Chi-squared 60% estimations used to calculate the failure rate.
[3] Thermal Acceleration Factor is calculated from the Arrhenius equation

$$AF = \exp\left[\frac{E_A}{k}\left[\frac{1}{T_2} - \frac{1}{T_1}\right]\right]$$

where:

E_A =The Activation Energy of the defect mechanism.
K = Boltzmann's constant = 8.62×10^{-5} eV/Kelvin.
T_1 is the junction temperature of the device under stress and T_2 is the junction temperature of the device at use conditions.

Reliability Test Data

QTP #: 151008

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	15	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	15	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 150C							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	80	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1000	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1000	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	80	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	76	80	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	152	79	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	76	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	152	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	76	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	152	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150, 2.07V, Vcc Max)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	48	1490	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	48	1510	0	
CYTT214032 (8CP206101)	4545249	611537364	CML-RA	48	1547	0	
STRESS: ENDURANCE							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	168	78	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	78	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	168	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	168	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	80	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	9	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	750	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1000	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1250	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1500	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1750	3	0	

Reliability Test Data

QTP #: 151008

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ESD-CHARGE DEVICE MODEL							
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	9	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	750	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1000	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1250	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1500	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1750	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	9	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	750	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1000	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1250	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1500	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1750	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1100	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	2200	8	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	3300	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	4000	3	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	5000	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	1100	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	2200	8	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	3300	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	4000	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1100	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	2200	8	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	3300	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	4000	3	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	96	30	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	96	30	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	80	116	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	116	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	80	120	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	120	0	

Reliability Test Data

QTP #: 151008

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: LOW TEMPERATURE OPERATING LIFE, -40C							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	160	40	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	380	40	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	168	75	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	168	78	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	168	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	288	80	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	10+2	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	10+2	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	10+2	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	6	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	6	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	6	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	3	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	COMP	3	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	COMP	3	0	
STRESS: SEM CROSS SECTION							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	1	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	500	80	0	
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	1000	80	0	
CYTT214032 (8CP206101)	4540145	611534709	CML-RA	500	80	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	500	79	0	
CY8C42452 (8CP44200)	4537464	611531543	CML-RA	1000	79	0	
STRESS: THERMAL JUNCTION MEASUREMENT							
CYTT214032 (8CP206101)	4539372	611534008	CML-RA	COMP	1	0	

Reliability Test Data

QTP #: 151403

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 150C							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	500	80	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	76	80	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	152	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	48	1510	0	
STRESS: ENDURANCE							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	168	80	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	500	80	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	500	9	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	750	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	1000	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	1250	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	1500	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	1750	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	2000	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	1100	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	2200	8	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	3300	3	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	4000	3	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	80	120	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	500	120	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	168	80	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	288	80	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	COMP	10+2	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	COMP	6	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	COMP	3	0	

Reliability Test Data

QTP #: 151403

Device	*Fab Lot #*	*Assy Lot #*	*Assy Loc*	*Duration*	*Samp*	*Rej*	*Failure Mechanism*
STRESS: STATIC LATCH-UP (85C, 300mA)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	500	79	0	
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	1000	79	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C42452A(8CP44200DB)	4537464	611531543	CML-R	48	1469	0	

Reliability Test Data

QTP #: 151303

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 150C							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	500	80	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	76	80	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	152	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	48	1469	0	
STRESS: ENDURANCE							
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	168	80	0	
CY8CMBR31552 (8CP44303CB)	4542914	611534693	ASE-G	500	80	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	500	9	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	750	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1250	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1500	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1750	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1100	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	2200	8	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	3300	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	4000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	5000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	6000	3	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	7000	3	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8CMBR31552(8CP44303CB)	4542914	611534693	ASE-G	80	120	0	
CY8CMBR31552(8CP44303CB)	4542914	611534693	ASE-G	500	120	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	168	80	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	288	79	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CY8CMBR31552(8CP44303CB)	4542914	611534693	ASE-G	COMP	10+2	0	

Reliability Test Data

QTP #: 151303

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	6	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	500	80	0	
CY8CMBR3106S2(8CP44304)	4542914	611534639	CML-RA	1000	80	0	

Reliability Test Data

QTP #: 160401

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 150C							
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	500	80	0	
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	1000	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	48	1550	0	
STRESS: ENDURANCE							
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	168	80	0	
CY8C42452(8CP44200DB)	4537464	611531543	CML-RA	1000	80	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	500	9	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	750	3	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	1000	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	1100	3	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	2200	3	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	3300	3	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	168	80	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	168	76	0	
STRESS: STATIC LATCH-UP (125C, 100mA)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	500	78	0	
CYFPA1 (8CP2F1001BB)	3609025	611610290	CML-R	1000	76	0	

Reliability Test Data

QTP #: 160301

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: DATA RETENTION, PLASTIC, 150C							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	80	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	76	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	152	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	48	2609	1	No Visual Defect found
CYAT816882 (8C206802BB)	3617006	611617664	CML-R	48	1013	0	
STRESS: ENDURANCE							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	80	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	9	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	750	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	3	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	500	9	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1000	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1250	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1500	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	1750	3	0	
CYTT417012 (8CP206801BB)	3613017	611614958	CML-R	2000	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1100	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	2200	8	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	3300	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	4000	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	5000	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	6000	3	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	7000	3	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	99	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	10	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	

Reliability Test Data

QTP #: 160301

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: STATIC LATCH-UP (85C, 140mA)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	500	80	0	
CYAT816882 (8C206802BB)	3613017	611611087	CML-R	1000	80	0	

Reliability Test Data

QTP #: 160803

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	48	1596	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	500	9	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	750	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1250	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1500	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	1100	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	2200	8	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	3300	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	4000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	5000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	6000	3	0	
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	7000	3	0	
STRESS: STATIC LATCH-UP (125C, 100Ma)							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140Ma)							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 140Ma)							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 200Ma)							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300Ma)							
CY8C4045 (8CP40003BB)	3615013	611612344	OSE-T	COMP	3	0	

Reliability Test Data

QTP #: 160207

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 150C							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	1000	90	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	76	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	152	90	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	48	2303	0	
STRESS: ENDURANCE							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	168	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	90	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	9	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	1100	3	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	2200	8	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	96	30	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 5.07V, Vcc Max)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	125	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	168	78	0	
STRESS: STATIC LATCH-UP (125C, 100mA)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	80	0	

Reliability Test Data

QTP #: 160702

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	COMP	15	0	
CY8C4246 (8CP480001BB)	4542101	611535695	CML-RA	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	76	80	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	152	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	48	1521	0	
CY8C4246 (8CP480001BB)	4542101	611535695	CML-RA	48	1532	0	
STRESS: ENDURANCE							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	168	80	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	500	9	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	750	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	1000	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	1250	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	1500	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	1750	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	2000	3	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	500	9	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	750	3	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	1000	3	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	1250	3	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	1500	3	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	1750	3	0	
CY8C4248 (8CP42005CB)	3621015	611619414	ASE-G	2000	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	1100	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	2200	8	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	3300	3	0	
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	4000	3	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	96	30	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 5.07V, Vcc Max)							
CY8C4246 (8CP480001BB)	4542101	611535695	CML-RA	80	80	0	
CY8C4246 (8CP480001BB)	4542101	611535695	CML-RA	500	80	0	

Reliability Test Data

QTP #: 160702

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	168	80	0	
STRESS: STATIC LATCH-UP (125C, 100mA)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8C4248 (8CP42003CB)	3621015	611619413	ASE-G	500	80	0	
CY8C4246 (8CP480001BB)	4542101	611535695	CML-RA	500	80	0	
CY8C4246 (8CP480001BB)	4542101	611535695	CML-RA	1000	80	0	

Reliability Test Data

QTP #: 160701

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	15	0	
CY8C4248 (8CP42003DB)	3649066	611701516	ASE-G	COMP	15	0	
CY8C4248 (8CP42003DB)	3649067	611701515	ASE-G	COMP	15	0	
STRESS: DATA RETENTION, PLASTIC, 150C							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	500	80	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1000	80	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	76	80	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	152	80	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	48	1598	0	
CY8C4248 (8CP42003DB)	3649066	611701516	ASE-G	48	1550	0	
STRESS: ENDURANCE							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	168	88	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	500	88	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	500	9	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	750	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1000	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1250	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1500	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1750	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	2000	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1000	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	2200	8	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	3300	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	4000	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	5000	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	6000	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	7000	3	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	8000	3	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	96	25	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	192	25	0	

Reliability Test Data

QTP #: 160701

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	80	80	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	500	80	0	
CY8C4248 (8CP42003DB)	3649066	611701516	ASE-G	500	80	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	96	80	0	
CY8C4248 (8CP42003DB)	3649066	611701516	ASE-G	168	80	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	12	0	
STRESS: STATIC LATCH-UP (125C, 100mA)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (85C, 300mA)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	500	80	0	
CY8C4248 (8CP42003CB)	3631019	611627888	ASE-G	1000	80	0	
CY8C4248 (8CP42003DB)	3649066	611701516	ASE-G	500	80	0	
CY8C4248 (8CP42003DB)	3649066	611701516	ASE-G	1000	80	0	
CY8C4248 (8CP42003DB)	3649067	611701515	ASE-G	500	80	0	
CY8C4248 (8CP42003DB)	3649067	611701515	ASE-G	1000	80	0	

Reliability Test Data

QTP #: 172307

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	48	1196	0	
CY8C4248 (8CP42003DB)	3721130	611729092	ASE-G	48	1200	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	500	9	0	
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	1000	3	0	
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	1250	3	0	
CY8C4248 (8CP42005DB)	3726090	611732045	ASE-G	500	9	0	
CY8C4248 (8CP42005DB)	3726090	611732045	ASE-G	1000	3	0	
CY8C4248 (8CP42005DB)	3726090	611732045	ASE-G	1250	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	1100	3	0	
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	2200	8	0	
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	3300	3	0	
STRESS: HI-ACCEL SATURATION TEST (130C, 85%RH, 5.5V), PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	96	30	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	500	80	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	168	80	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	12	0	
STRESS: STATIC LATCH-UP (125C, 100mA)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	2	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	2	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	2	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	80	0	
CY8C4248 (8CP42003DB)	3721130	611724119	ASE-G	COMP	78	0	

Reliability Test Data

QTP #: 173204

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	48	537	0	
CY8C4147 (8CP43002AB)	3739025	611738647	ASE-G	48	1090	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	500	9	0	
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1000	3	0	
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1250	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1100	3	0	
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	2200	8	0	
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	3300	3	0	
STRESS: STATIC LATCH-UP (125C, 100mA)							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1100	3	0	
STRESS: STATIC LATCH-UP (125C, 140mA)							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1100	3	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1100	3	0	
STRESS: STATIC LATCH-UP (85C, 200mA)							
CY8C4147 (8CP43002AB)	3738085	611737095	ASE-G	1100	3	0	

Reliability Test Data

QTP #: 162806

Device	Fab Lot #	Assy Lot #	Assy Loc	Duration	Samp	Rej	Failure Mechanism
STRESS: ACOUSTIC, MSL3							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	COMP	22	0	
STRESS: ENDURANCE							
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	CYCLING	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	168	90	0	
CY8C3866A (8CP38661HB)	3617013	611615839	CML-R	500	90	0	
STRESS: ESD-CHARGE DEVICE MODEL							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	500	9	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	750	3	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	1000	3	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	1250	3	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	1500	3	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	1750	3	0	
STRESS: ESD-HUMAN BODY MODEL PER JESD22, METHOD A114							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	1100	3	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	2200	3	0	
STRESS: DATA RETENTION, PLASTIC, 175C							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	76	22	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	152	22	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-EARLY FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	48	1545	0	
STRESS: HIGH TEMP DYNAMIC OPERATING LIFE-LATENT FAILURE RATE (150C, 2.07V, Vcc Max)							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	80	120	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	500	120	0	
STRESS: PRESSURE COOKER TEST (121C, 100%RH), 15 Psig, PRE COND 192 HR 30C/60%RH (MSL3)							
CY8C5668(8C561001CB)	3732049	611731960	CML-R	168	80	0	
CY8C5668(8C561001CB)	3732049	611731960	CML-R	288	78	0	
STRESS: PRE/POST LFR PARAMETER ASSESSMENT							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	COMP	10+2	0	
STRESS: STATIC LATCH-UP (85C, 140mA)							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	COMP	3	0	
STRESS: TC COND. C -65C TO 150C, PRE COND 192 HRS 30C/60%RH (MSL3)							
CY8C5668(8C561001CB)	3708110	611711571	CML-R	500	84	0	
CY8C5668(8C561001CB)	3708110	611711571	CML-R	1000	84	0	

Document History Page

Document Title: QTP#162806: PSoC5 LP Device Family S8PM-10P Technology, Fab25
Document Number: 002-24322

Rev.	ECN No.	Orig. of Change	Description of Change
**	6212734	HSTO	Initial Spec Release
*A	7799935	SLLO	Rebranding to PSoC™ Multitouch in PACKAGE/PRODUCT QUALIFICATION HISTORY table for QTP 160401, and 160301. Aligned header and footer with template 002-33284.